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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/733,289	12/08/2000	Xiao-Chun Mu	42390P8875	2980
21186 7590 03/21/2007 SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A. P.O. BOX 2938 MINNEAPOLIS, MN 55402			EXAMINER NGUYEN, DILINH P	
			ART UNIT	PAPER NUMBER
			2814	
SHORTENED STATUTORY PERIOD OF RESPONSE		MAIL DATE	DELIVERY MODE	
3 MONTHS		03/21/2007	PAPER	

Please find below and/or attached an Office communication concerning this application or proceeding.

If NO period for reply is specified above, the maximum statutory period will apply and will expire 6 MONTHS from the mailing date of this communication.

Office Action Summary

Application No.

09/733,289

Applicant(s)

MU ET AL.

Examiner

DiLinh Nguyen

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-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 28 December 2006.
- 2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-4, 10-17 and 29 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 1-4, 10-17, 29 is/are rejected.
- 7) ☐ Claim(s) _____ is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on _____ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some * c) ☐ None of:
- ☐ Certified copies of the priority documents have been received.
 - ☐ Certified copies of the priority documents have been received in Application No. _____.
 - ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
- * See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- | | |
|--|---|
| 1) <input type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413)
Paper No(s)/Mail Date. _____ |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | 5) <input type="checkbox"/> Notice of Informal Patent Application |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO/SB/08)
Paper No(s)/Mail Date _____ | 6) <input type="checkbox"/> Other: _____ |

DETAILED ACTION

Claim Rejections - 35 USC § 103

1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

2. Claim 1 is rejected under 35 U.S.C. 103(a) as being unpatentable over Chen et al. (U.S. Pat. 6160311) in view of Jimarez et al. (U.S. Pat. 6407334).

Chen et al. disclose a semiconductor device (cover fig., figs. 4H and 5A) comprising:

a planar heat sink 32a (column 3, lines 30-31);
more than one microelectronic die 31a (fig. 5A), each having an active surface and a back surface, wherein said more than one microelectronic die back surface adjacent to the heat sink;
a patterned adhesive layer 33a disposed between said more than one microelectronic die 31a and the heat sink 32a; and
an encapsulation material 36a (column 3, lines 58-59) disposed on the heat sink and the microelectronic die active surface.

Chen et al. do not explicitly disclose the patterned adhesive layer 33a is a patterned thermally conductive adhesive.

However, Jimarez et al. disclose a patterned thermally conductive adhesive layer 44 (cover fig., column 3, lines 27-28) disposed between a chip 34 and a planar heat sink

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46. Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the device of Chen et al. by having the patterned thermally conductive adhesive layer disposed between the chip and the heat sink because as taught by Jimarez et al., such the patterned thermally conductive adhesive layer would increase the heat dissipation between the die and the planar heat sink.

3. Claim 29 is rejected under 35 U.S.C. 103(a) as being unpatentable over Chen et al. (U.S. Pat. 6160311) in view of Jimarez et al. (U.S. Pat. 6407334) as applied to claim 1 above, and further in view of Woodward et al. (U.S. Pat. 4731700).

Chen et al. in view of Jimarez et al. substantially disclose all the limitations as claimed above except for a microelectronic package core and wherein the die is disposed within at least one package core opening.

However, Woodward et al. disclose a semiconductor device (fig. 2, column 4, lines 12-24) comprising:

a ceramic member 14 having a first surface and an opposing second surface, the ceramic member having at least one opening defined therein extending from the ceramic member first surface to the ceramic member second surface, where the ceramic member second surface abuts the planar heat sink 12; and wherein a die 16 is disposed within the ceramic member opening and adjacent the heat sink, the die having an active surface. Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to have the microelectronic package core and wherein the die is disposed within at least one package core opening as taught by Woodward et al. into the device structure of Chen et

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al. in view of Jimarez et al. in order to provide an electrical crossover in the area above the die and increase in interconnect density.

4. Claims 1-4 are rejected under 35 U.S.C. 103(a) as being unpatentable over Eichelberger (U.S. Pat. 5250843) in view of Jimarez et al. (U.S. Pat. 6407334).

Eichelberger discloses a semiconductor device (fig. 1, column 13, lines 51 et seq.) comprising:

a planar heat sink 12 ;

more than one microelectronic die 14, each having an active surface and a back surface, said more than one microelectronic die back surface adjacent to the heat sink;

a thin die attach material 16 disposed between more than one microelectronic die and the heat sink (column 13, lines 64-66); and

an encapsulation material 18 disposed on the heat sink and the die active surface.

Eichelberger does not disclose a thin die attach material 16 is a patterned thermally conductive adhesive layer.

However, Jimarez et al. disclose a patterned thermally conductive adhesive layer 44 (cover fig., column 3, lines 27-28) disposed between a chip 34 and a planar heat sink 46. Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the device of Eichelberger by having the patterned thermally conductive adhesive layer disposed between the chip and the heat sink because as taught by Jimarez et al., such the patterned thermally conductive

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adhesive layer would increase the heat dissipation between the die and the planar heat sink.

- Regarding claim 2, Eichelberger discloses a build up layer disposed on an upper surface of the encapsulant material.
- Regarding claim 3, Eichelberger discloses the build up layer comprises at least on conductive trace 20 disposed on the encapsulation material upper surface, wherein a portion of the conductive trace extending through the encapsulation material to contact the microelectronic die active surface.
- Regarding claim 4, Eichelberger discloses the build up layer further includes at least one dielectric layer 24 disposed on at least a portion of the encapsulation material upper surface and at least on conductive trace, and at least one second conductive trace 26 extending through the dielectric layer to contact the conductive trace.

5. Claim 29 is rejected under 35 U.S.C. 103(a) as being unpatentable over Eichelberger (U.S. Pat. 5250843) in view of Jimarez et al. (U.S. Pat. 6407334) as applied to claim 1 above, and further in view of Woodward et al. (U.S. Pat. 4731700).

Eichelberger in view of Jimarez et al. substantially disclose all the limitations as claimed above except for a microelectronic package core and wherein the die is disposed within at least one package core opening.

However, Woodward et al. disclose a semiconductor device (fig. 2, column 4, lines 12-24) comprising:

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a ceramic member 14 having a first surface and an opposing second surface, the ceramic member having at least one opening defined therein extending from the ceramic member first surface to the ceramic member second surface, where the ceramic member second surface abuts the planar heat sink 12; and wherein at least one die 16 is disposed within the ceramic member opening and adjacent the heat sink, the die having an active surface. Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to have the microelectronic package core and wherein the die is disposed within at least one package core opening as taught by Woodward et al. into the device structure of Eichelberger in view of Jimarez et al. in order to provide an electrical crossover in the area above the die and increase in interconnect density.

6. Claims 10 and 15-16 are rejected under 35 U.S.C. 103(a) as being unpatentable over Shen (U.S. Pat. 6368894) in view of Woodward et al. (U.S. Pat. 4731700).

Shen discloses a semiconductor device (figs. 1-2, column 4, lines 5 et seq.) comprising:

a planar heat sink 33 (column 5, lines 27);

a package core 1 having a first surface 10 and an opposing second surface 14, the package core having at least one opening 11 (fig. 2) defined therein extending from the package core first surface to the package core second surface;

more than one microelectronic die 3 (column 5, lines 30) disposed within at least one package core opening and adjacent the heat sink, each said more than one microelectronic die having an active surface; and

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an encapsulation material 34 disposed on the die and in portions of at least one package core opening.

Shen does not disclose the microelectronic package core second surface abuts the heat sink.

However, Woodward et al. disclose a semiconductor device (fig. 2, column 4, lines 12-24) comprising: a ceramic member 14 having a first surface and an opposing second surface, wherein the ceramic member second surface abuts a planar heat sink 12. Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to have the microelectronic package core second surface abuts the heat sink as taught by Woodward et al. into the device structure of Shen in order to provide good heat dissipation for the semiconductor package device.

- Regarding claim 15, Woodward et al. disclose a thickness of the ceramic member 14 is greater than a thickness of the die 16 (fig. 2).
- Regarding claim 16, Shen discloses the package core is a material selected from the group consisting of ceramics or metals (column 4, lines 5-10).

7. Claims 11-14 are rejected under 35 U.S.C. 103(a) as being unpatentable over Shen (U.S. Pat. 6368894) in view of Woodward et al. (U.S. Pat. 4731700) as applied to claim 10 above, and further in view of Eichelberger (U.S. Pat. 5250843).

Shen in view of Woodward et al. substantially disclose all the limitations as claimed above except for a build up layer disposed on an upper surface of the encapsulation material.

However, Eichelberger discloses a semiconductor device (fig. 1, column 13, lines 51 et seq.) comprising: a build up layer disposed on an upper surface of the encapsulation material 18 to provide interconnection pads (column 10, lines 54-57). Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the device of Shen in view of Woodward et al. by having the build up layer disposed on an upper surface of the encapsulation material because as taught by Eichelberger, such the build up layer would provide a direct interconnection between integrated circuit chips.

- Regarding claim 12, Eichelberger discloses the build up layer comprises at least on conductive trace 20 disposed on the encapsulation material upper surface, wherein a portion of the conductive trace extending through the encapsulation material to contact the microelectronic die active surface.
- Regarding claim 13, Eichelberger discloses the build up layer further includes at least one dielectric layer 24 disposed on at least a portion of the encapsulation material upper surface and at least on conductive trace, and at least one second conductive trace 26 extending through the dielectric layer to contact the conductive trace.
- Regarding claim 14, Shen discloses the encapsulation (34 and 24) covers the package core first surface.

8. Claim 17 is rejected under 35 U.S.C. 103(a) as being unpatentable over Shen (U.S. Pat. 6368894) in view of Woodward et al. (U.S. Pat. 4731700) as applied to claim 10 above, and further in view of Jimarez et al. (U.S. Pat. 6407334).

Shen in view of Woodward et al. substantially disclose all the limitations as claimed above except for a thermally conductive adhesive layer disposed between the microelectronic die and the planar heat sink.

However, Jimarez et al. disclose a patterned thermally conductive adhesive layer 44 (cover fig., column 3, lines 27-28) disposed between a die 34 and a planar heat sink 46. Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the device of Shen in view of Woodward et al. by having the patterned thermally conductive adhesive layer disposed between the chip and the heat sink because as taught by Jimarez et al., such the thermally conductive adhesive layer would increase the heat dissipation between the die and the planar heat sink.

Conclusion

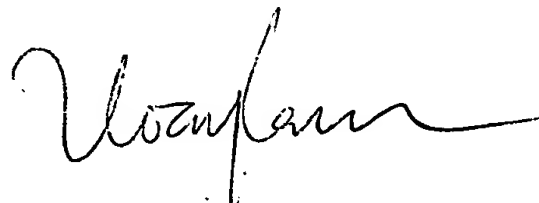
Any inquiry concerning this communication or earlier communications from the examiner should be directed to DiLinh Nguyen whose telephone number is (571) 272-1712. The examiner can normally be reached on 8:00AM - 5:00PM (M-F).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Wael Fahmy can be reached on (571) 272-1705. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

DLN



HOAI PHAM
PRIMARY EXAMINER